

# NDF0610 / NDS0610

## P-Channel Enhancement Mode Field Effect Transistor

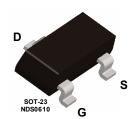
### **General Description**

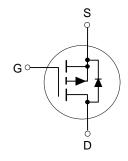
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. They can be used, with a minimum of effort, in most applications requiring up to 180mA DC and can deliver pulsed currents up to 1A. This product is particularly suited to low voltage applications requiring a low current high side switch.

#### **Features**

- -0.18 and -0.12A, -60V.  $R_{DS(ON)} = 10\Omega$
- Voltage controlled p-channel small signal switch
- High density cell design for low R<sub>DS(ON)</sub>
- TO-92 and SOT-23 packages for both through hole and surface mount applications
- High saturation current







### **Absolute Maximum Ratings**

T<sub>A</sub> = 25°C unless otherwise noted

| Symbol            | Parameter   | NDF0610    | NDS0610 | Units |
|-------------------|---|------------|---------|-------|
| V <sub>DSS</sub>  | Drain-Source Voltage  | -60        |         | V     |
| $V_{DGR}$         | Drain-Gate Voltage ( $R_{gs} \le 1 \text{ M}\Omega$ )                           | -60        |         | V     |
| V <sub>GSS</sub>  | Gate-Source Voltage - Continuous  | ±20        | V       |       |
|                   | - Nonrepetitive (t <sub>P</sub> < 50 µs)  | ±30        | V       |       |
| I <sub>D</sub>    | Drain Current - Continuous  | -0.18      | -0.12   | А     |
|                   | - Pulsed  | -1         |         |       |
| P <sub>D</sub>    | Maximum Power Dissipation T <sub>A</sub> = 25°C                                 | 0.8        | 0.36    | W     |
|                   | Derate above 25°C   | 5          | 2.9     | mW/°C |
| $T_J$ , $T_{STG}$ | Operating and Storage Temperature Range   | -55 to 150 |         | °C    |
| T <sub>L</sub>    | Maximum lead temperature for soldering purposes, 1/16" from case for 10 seconds | 300        |         | °C    |
| THERMA            | L CHARACTERISTICS   |            |         |       |
| $R_{\theta JA}$   | Thermal Resistance, Junction-to-Ambient   | 200        | 350     | °C/W  |

| Symbol              | Parameter                             | Conditions   |                        | Min      | Тур      | Max   | Units |
|---------------------|---------------------------------------|--|------------------------|----------|----------|-------|-------|
| OFF CHA             | ARACTERISTICS                         | -  |                        | <u>I</u> | 1        |       | ·L    |
| 3V <sub>DSS</sub>   | Drain-Source Breakdown Voltage        | $V_{GS} = 0 \text{ V}, I_{D} = -10 \mu\text{A}$  |                        | -60      |          |       | V     |
| DSS                 | Zero Gate Voltage Drain Current       | $V_{DS} = -48 \text{ V}, V_{GS} = 0 \text{ V}$   |                        |          |          | -1    | μA    |
|                     |                                       |  | T <sub>J</sub> = 125°C |          |          | -200  | μA    |
| GSSF                | Gate - Body Leakage, Forward          | $V_{gs} = 20 \text{ V}, V_{ps} = 0 \text{ V}$  |                        |          |          | 10    | nA    |
| GSSR                | Gate - Body Leakage, Reverse          | $V_{gs} = -20 \text{ V}, V_{DS} = 0 \text{ V}$   |                        |          |          | -10   | nA    |
| ON CHAI             | RACTERISTICS (Note 1)                 | <u>.</u>   |                        | •        |          |       |       |
| $V_{GS(th)}$        | Gate Threshold Voltage                | $V_{DS} = V_{GS}$ , $I_D = -1 \text{ mA}$  |                        | -1       | -2.4     | -3.5  | V     |
|                     |                                       |  | T <sub>J</sub> = 125°C | -0.6     | -2.1     | -3.2  |       |
| R <sub>DS(ON)</sub> | Static Drain-Source On-Resistance     | $V_{GS} = -10 \text{ V}, I_{D} = -0.5 \text{ A}$   | •                      |          | 3.6      | 10    | Ω     |
|                     |                                       |  | T <sub>J</sub> = 125°C |          | 5.9      | 16    |       |
|                     |                                       | $V_{gs} = -4.5 \text{ V}, I_{D} = -0.25 \text{ A}$   |                        |          | 5.2      | 20    |       |
|                     |                                       |  | T <sub>J</sub> = 125°C |          | 7.9      | 30    |       |
| D(on)               | On-State Drain Current                | $V_{GS} = -10 \text{ V}, V_{DS} = -10 \text{ V}$   | •                      | -0.6     | -1.6     |       | Α     |
|                     |                                       | $V_{GS} = -4.5 \text{ V}, V_{DS} = -10 \text{ V}$  |                        |          | -0.35    |       |       |
| FS                  | Forward Transconductance              | $V_{DS} = -10 \text{ V}, I_{D} = -0.1 \text{ A}$   |                        | 70       | 170      |       | mS    |
| OYNAMIC             | CCHARACTERISTICS                      | ·  |                        |          |          |       |       |
| Siss                | Input Capacitance                     | $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$                      |                        |          | 40       | 60    | pF    |
| Coss                | Output Capacitance                    |  |                        |          | 11       | 25    | pF    |
| C <sub>rss</sub>    | Reverse Transfer Capacitance          |  |                        |          | 3.2      | 5     | pF    |
|                     | NG CHARACTERISTICS (Note 1)           |  |                        |          |          |       |       |
| D(on)               | Turn - On Delay Time                  | $V_{DD} = -25 \text{ V}, I_{D} = -0.18 \text{ A},$   |                        |          | 7        | 10    | nS    |
| r                   | Turn - On Rise Time                   | $V_{GS} = -10 \text{ V}, R_{GEN} = 25 \Omega$  |                        |          | 5        | 15    | nS    |
| D(off)              | Turn - Off Delay Time                 |  |                        |          | 13       | 15    | nS    |
| f                   | Turn - Off Fall Time                  |  |                        |          | 10       | 20    | nS    |
| $Q_g$               | Total Gate Charge                     | $V_{DS} = -48 \text{ V},$ $I_{D} = -0.5 \text{ A}, V_{GS} = -10 \text{ V}$                 |                        |          | 1.43     |       | nC    |
| $\mathbf{Q}_{gs}$   | Gate-Source Charge                    |  |                        |          | 0.6      |       | nC    |
| $Q_{qd}$            | Gate-Drain Charge                     |  |                        |          | 0.25     |       | nC    |
|                     | DURCE DIODE CHARACTERISTICS           |  |                        | I        | <u> </u> |       | 1     |
| s                   | Maximum Continuous Source Current     |  |                        |          |          | -0.18 | Α     |
| SM                  | Maximum Pulse Source Current (Note 1) |  |                        |          |          | -1    | Α     |
| V <sub>SD</sub>     | Drain-Source Diode Forward Voltage    | $V_{GS} = 0 \text{ V}, I_{S} = -0.5 \text{ A}$ (Note 1)                                    |                        |          | -1.2     | -1.5  | V     |
|                     |                                       | (Note 1)   | T <sub>J</sub> = 125°C |          | -0.98    | -1.3  | 1     |
| rr                  | Reverse Recovery Time                 | $V_{GS} = 0 \text{ V}, I_{S} = -0.5 \text{ A},$<br>$dI_{F}/dt = 100 \text{ A/}\mu\text{s}$ | •                      |          | 40       |       | ns    |
|                     | Reverse Recovery Current              | dI <sub>F</sub> /dt = 100 A/μs   |                        |          | 2.8      |       | Α     |

Note: 1. Pulse Test: Pulse Width  $\leq$  300  $\mu$ s, Duty Cycle  $\leq$  2.0%.

# **Typical Electrical Characteristics**

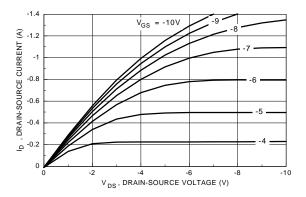


Figure 1. On-Region Characteristics

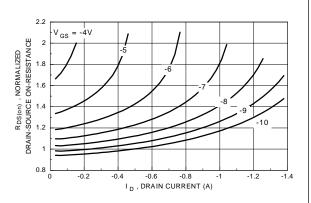


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current

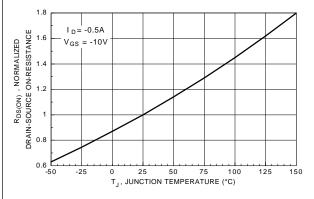


Figure 3. On-Resistance Variation with Temperature

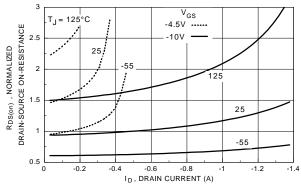


Figure 4. On-Resistance Variation with Drain Current and Temperature

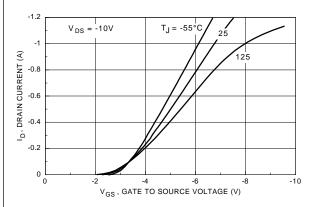


Figure 5. Transfer Characteristics

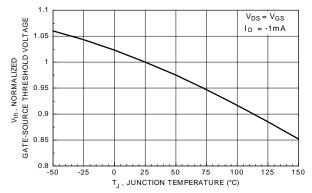


Figure 6. Gate Threshold Variation with Temperature

# **Typical Electrical Characteristics (continued)**

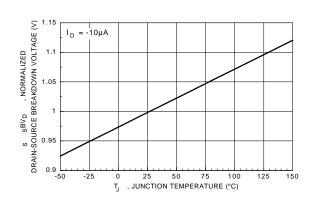


Figure 7. Breakdown Voltage Variation with Temperature

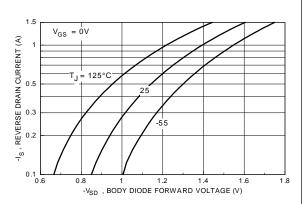


Figure 8. Body Diode Forward Voltage
Variation with Current and Temperature

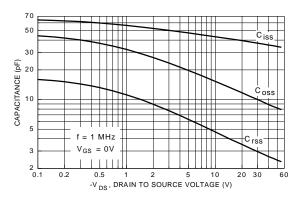


Figure 9. Capacitance Characteristics

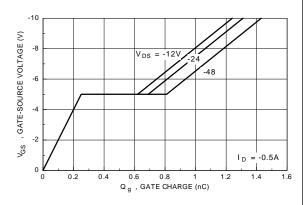


Figure 10. Gate Charge Characteristics

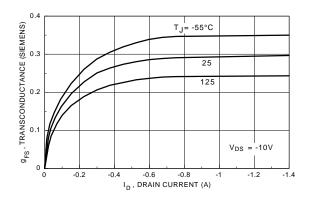


Figure 11. Transconductance Variation with Drain Current and Temperature

# **Typical Electrical Characteristics** (continued)

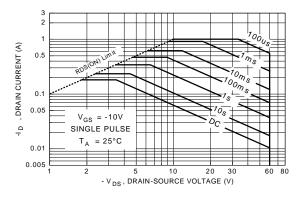


Figure 12. NDF0610 (TO-92)

Maximum Safe Operating Area

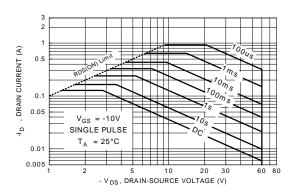


Figure 13. NDS0610 (SOT-23) Maximum Safe Operating Area

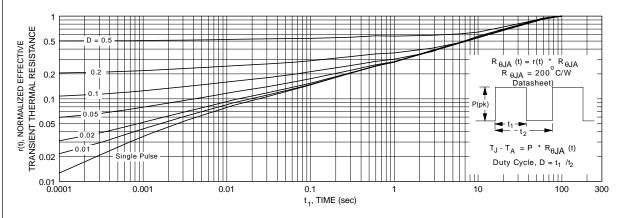


Figure 14. NDF0610 (TO-92) Transient Thermal Response Curve.

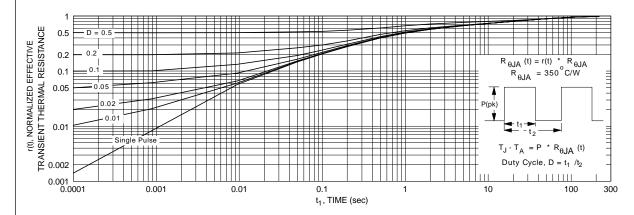


Figure 15. NDS0610 (SOT-23) Transient Thermal Response Curve.

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|--------------------------|---------------------------|---|
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